



NOTES/SPECIFICATIONS:

1. CLEAR APERTURE (S1): > 80% DIAMETER
2. SURFACE FLATNESS (S1): λ/10 AT 632.8 nm OVER CLEAR APERTURE
3. SURFACE QUALITY (S1): 40-20 SCRATCH-DIG
4. BACK SURFACE (S2): FINE GROUND
5. PARALLELISM: ≤ 3 arcmin
6. THICKNESS TOLERANCE: ±0.20 mm
7. DIAMETER TOLERANCE: +0.00/-0.10 mm
8. COATING (S1): ULTRAFAST ENHANCED SILVER
   WAVELENGTH RANGE: 750 - 1000 nm, 45° AOI
   S-POLARIZATION: R(abs) >99.0%, |GDD| < 20 fs²
   P-POLARIZATION: R(abs) >98.5%, |GDD| < 30 fs²

FOR INFORMATION ONLY
NOT FOR MANUFACTURING PURPOSES

DRAWING PROJECTION		
	NAME	DATE
DRAWN	KP	03/APR/17
APPROVAL	DS	07/AUG/25

COPYRIGHT © 2017 BY THORLABS

VALUES IN PARENTHESIS ARE CALCULATED AND MAY CONTAIN ROUNDOFF ERRORS

THORLABS
www.thorlabs.com

Ø0.5" ENHANCED SILVER MIRROR, 750 nm - 1000 nm, 45° AOI

MATERIAL	REV
FUSED SILICA	C

ITEM #	APPROX WEIGHT
UM05-AG	2 g